

# NX3008NBKT

# 30 V, 350 mA N-channel Trench MOSFET Rev. 1 — 1 August 2011

Product data sheet

## **Product profile**

## 1.1 General description

N-channel enhancement mode Field-Effect Transistor (FET) in a small SOT416 (SC-75) Surface-Mounted Device (SMD) plastic package using Trench MOSFET technology.

## 1.2 Features and benefits

- Very fast switching
- Low threshold voltage
- Trench MOSFET technology
- ESD protection up to 2 kV
- AEC-Q101 qualified

## 1.3 Applications

- Relay driver
- High-speed line driver

- Low-side loadswitch
- Switching circuits

#### 1.4 Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{DS}$	drain-source voltage	T <sub>j</sub> = 25 °C	-	-	30	V
$V_{GS}$	gate-source voltage		-8	-	8	V
$I_D$	drain current	$V_{GS} = 4.5 \text{ V};$ $T_{amb} = 25 \text{ °C}$	[1] -	-	350	mA
Static char	racteristics					
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS} = 4.5 \text{ V}; I_D = 350 \text{ mA};$ $T_j = 25 \text{ °C}$	-	1	1.4	Ω

<sup>[1]</sup> Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for drain 1 cm<sup>2</sup>.



# 2. Pinning information

Table 2. Pinning information

10010 21		, iiii oi iii atioii		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		
2	S	source		D
3	D	drain	1 2 SOT416 (SOT416)	S 017aaa255

# 3. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
NX3008NBKT	SOT416	plastic surface-mounted package; 3 leads	SOT416

# 4. Marking

Table 4. Marking codes

Type number	Marking code <sup>[1]</sup>
NX3008NBKT	AA

[1] % = placeholder for manufacturing site code

# 5. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Parameter	Conditions		Min	Max	Unit
drain-source voltage	$T_j = 25  ^{\circ}C$		-	30	V
gate-source voltage			-8	8	V
drain current	V <sub>GS</sub> = 4.5 V; T <sub>amb</sub> = 25 °C	[1]	-	350	mA
	$V_{GS} = 4.5 \text{ V}; T_{amb} = 100 ^{\circ}\text{C}$	[1]	-	230	mΑ
peak drain current	$T_{amb} = 25$ °C; single pulse; $t_p \le 10 \mu s$		-	1.4	Α
total power dissipation	T <sub>amb</sub> = 25 °C	[2]	-	250	mW
		[1]	-	300	mW
	T <sub>sp</sub> = 25 °C		-	770	mW
junction temperature			-55	150	°C
ambient temperature			-55	150	°C
storage temperature			-65	150	°C
diode					
source current	T <sub>amb</sub> = 25 °C	[1]	-	300	mA
n rating					
electrostatic discharge voltage	НВМ	[3]	-	2000	V
	drain-source voltage gate-source voltage drain current  peak drain current total power dissipation  junction temperature ambient temperature storage temperature diode source current rating	$ \begin{array}{lll} & & & & & & & & & & & \\ & & & & & & & $	$ \begin{array}{c} \text{drain-source voltage} & T_{j} = 25 \ ^{\circ}\text{C} \\ \\ \text{gate-source voltage} \\ \\ \text{drain current} & V_{GS} = 4.5 \ ^{\circ}\text{C}; \ T_{amb} = 25 \ ^{\circ}\text{C} \\ \hline V_{GS} = 4.5 \ ^{\circ}\text{C}; \ T_{amb} = 100 \ ^{\circ}\text{C} \\ \hline 11 \\ \text{peak drain current} & T_{amb} = 25 \ ^{\circ}\text{C}; \ \text{single pulse}; \ t_{p} \leq 10 \ ^{\mu}\text{S} \\ \hline 12 \\ \hline 13 \\ \hline 14 \\ \hline 15 \\ \hline 15 \\ \hline 16 \\ \hline 16 \\ \hline 16 \\ \hline 17 \\ \hline 17 \\ \hline 17 \\ \hline 18 \\ \hline 18 \\ \hline 19 \\ \hline 10 \\ \hline 11 \\ \hline 11 \\ \hline 11 \\ \hline 12 \\ \hline 13 \\ \hline 14 \\ \hline 15 \\ \hline 15 \\ \hline 16 \\ \hline 16 \\ \hline 17 \\ \hline 17 \\ \hline 17 \\ \hline 17 \\ \hline 18 \\ \hline 18 \\ \hline 18 \\ \hline 19 \\ \hline 19 \\ \hline 10 \\ 10 \\$	$ \begin{array}{c} drain\text{-source voltage} \\ gate\text{-source voltage} \\ drain current \\ \hline \\ QGS = 4.5 \text{ V; } T_{amb} = 25 \text{ °C} \\ \hline \\ V_{GS} = 4.5 \text{ V; } T_{amb} = 100 \text{ °C} \\ \hline \\ Peak drain current \\ \hline \\ T_{amb} = 25 \text{ °C; single pulse; } t_p \leq 10 \text{ µs} \\ \hline \\ T_{amb} = 25 \text{ °C} \\ \hline \\ T_{sp} = 25 \text{ °C} \\ \hline \\ T_{sp} = 25 \text{ °C} \\ \hline \\ III = -100000000000000000000000000000000000$	$ \begin{array}{c ccccccccccccccccccccccccccccccccccc$

 $<sup>\</sup>label{eq:condition} \textbf{[1]} \quad \text{Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for drain 1 cm$^2$.}$ 

<sup>[2]</sup> Device mounted on an FR4 Printed-Circuit Board (PCB), single-sided copper, tin-plated and standard footprint.

<sup>[3]</sup> Measured between all pins.

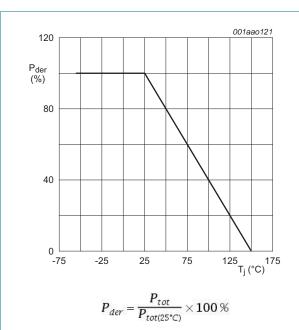


Fig 1. Normalized total power dissipation as a function of junction temperature

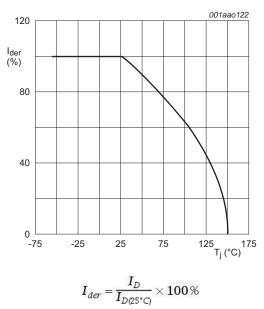
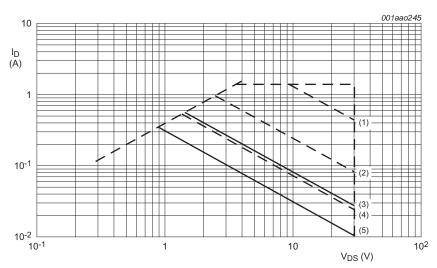


Fig 2. Normalized continuous drain current as a function of junction temperature



I<sub>DM</sub> is a single pulse

- (1)  $t_p = 1 \text{ ms}$
- (2)  $t_p = 10 \text{ ms}$
- (3) DC;  $T_{sp} = 25 \, ^{\circ}\text{C}$
- (4)  $t_p = 100 \text{ ms}$
- (5) DC;  $T_{amb} = 25 \text{ °C}$ ; 1 cm<sup>2</sup> drain mounting pad

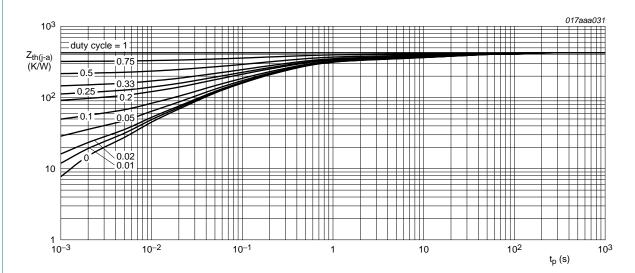
Fig 3. Safe operating area; junction to ambient; continuous and peak drain currents as a function of drain-source voltage

## 6. Thermal characteristics

Table 6. Thermal characteristics

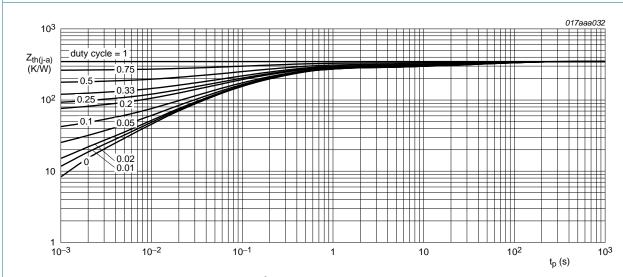
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{th(j-a)}$	thermal resistance from junction to ambient	in free air	<u>[1]</u> -	440	510	K/W
			[2] _	360	415	K/W
R <sub>th(j-sp)</sub>	thermal resistance from junction to solder point		-	-	160	K/W

- [1] Device mounted on an FR4 PCB, single-sided copper, tin-plated and standard footprint.
- [2] Device mounted on an FR4 PCB, single-sided copper, tin-plated, mounting pad for drain 1 cm<sup>2</sup>.



FR4 PCB, standard footprint

Fig 4. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values



FR4 PCB, mounting pad for drain 1 cm<sup>2</sup>

Fig 5. Transient thermal impedance from junction to ambient as a function of pulse duration; typical values

## 7. Characteristics

Table 7. Characteristics

Table 7.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	aracteristics					
V <sub>(BR)DSS</sub>	drain-source breakdown voltage	$I_D = 250 \mu A; V_{GS} = 0 V; T_j = 25 °C$	30	-	-	V
$V_{GSth}$	gate-source threshold voltage	$I_D = 250 \mu A; V_{DS} = V_{GS}; T_j = 25 \text{ °C}$	0.6	0.9	1.1	V
I <sub>DSS</sub>	drain leakage current	$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	-	1	μΑ
		$V_{DS} = 30 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 150 \text{ °C}$	-	-	10	μΑ
I <sub>GSS</sub>	gate leakage current	$V_{GS} = 8 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.2	1	μΑ
		$V_{GS} = -8 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	0.2	1	μΑ
		$V_{GS} = 4.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	10	-	nΑ
		$V_{GS} = -4.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	10	-	nΑ
		$V_{GS} = 2.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	1	-	nΑ
		$V_{GS} = -2.5 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$	-	1	-	nΑ
R <sub>DSon</sub>	drain-source on-state resistance	$V_{GS} = 4.5 \text{ V}; I_D = 350 \text{ mA}; T_j = 25 \text{ °C}$	-	1	1.4	Ω
		$V_{GS} = 4.5 \text{ V}; I_D = 350 \text{ mA}; T_j = 150 \text{ °C}$	-	1.8	2.5	Ω
		$V_{GS} = 2.5 \text{ V}; I_D = 200 \text{ mA}; T_j = 25 \text{ °C}$	-	1.4	2.1	Ω
		$V_{GS} = 1.8 \text{ V}; I_D = 10 \text{ mA}; T_j = 25 \text{ °C}$	-	2	2.8	Ω
9 <sub>fs</sub>	forward transconductance	$V_{DS} = 10 \text{ V}; I_D = 350 \text{ mA}; T_j = 25 \text{ °C}$	-	310	-	mS
Dynamic	characteristics					
Q <sub>G(tot)</sub>	total gate charge	$V_{DS} = 15 \text{ V}; I_D = 350 \text{ mA}; V_{GS} = 4.5 \text{ V};$	-	0.52	0.68	nC
$Q_{GS}$	gate-source charge	$T_j = 25 ^{\circ}\text{C}$	-	0.17	-	nC
$Q_GD$	gate-drain charge		-	0.08	-	nC
C <sub>iss</sub>	input capacitance	$V_{DS} = 15 \text{ V}; f = 1 \text{ MHz}; V_{GS} = 0 \text{ V};$	-	34	50	pF
C <sub>oss</sub>	output capacitance	$T_j = 25  ^{\circ}C$	-	6.5	-	рF
C <sub>rss</sub>	reverse transfer capacitance		-	2.2	-	pF
d(on)	turn-on delay time	$V_{DS}$ = 20 V; $R_L$ = 250 $\Omega$ ; $V_{GS}$ = 4.5 V;	-	15	30	ns
r	rise time	$R_{G(ext)} = 6 \Omega; T_j = 25 °C$	-	11	-	ns
d(off)	turn-off delay time		-	69	138	ns
f	fall time		-	19	-	ns
Source-d	rain diode					
$V_{SD}$	source-drain voltage	$I_S = 350 \text{ mA}; V_{GS} = 0 \text{ V}; T_i = 25 \text{ °C}$	0.47	0.85	1.2	V

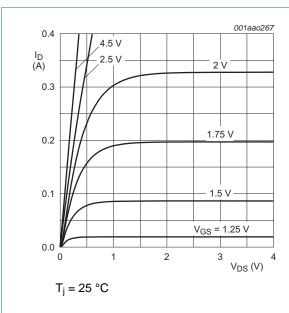
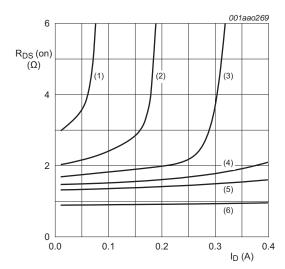


Fig 6. Output characteristics: drain current as a function of drain-source voltage; typical values



T<sub>i</sub> = 25 °C

(1)  $V_{GS} = 1.5 \text{ V}$ 

(2)  $V_{GS} = 1.75 \text{ V}$ 

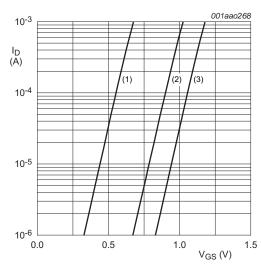
(3)  $V_{GS} = 2.0 \text{ V}$ 

(4)  $V_{GS} = 2.25 \text{ V}$ 

(5)  $V_{GS} = 2.5 \text{ V}$ 

(6)  $V_{GS} = 4.5 \text{ V}$ 

Fig 8. Drain-source on-state resistance as a function of drain current; typical values



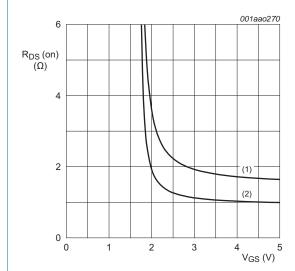
 $T_j = 25 \, ^{\circ}C; \, V_{DS} = 5 \, V$ 

(1) minimum values

(2) typical values

(3) maximum values

Fig 7. Sub-threshold drain current as a function of gate-source voltage

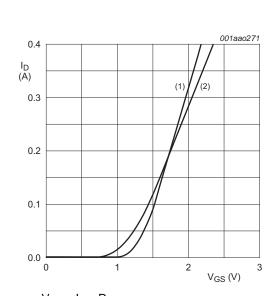


 $I_D = 350 \text{ mA}$ 

(1)  $T_i = 150 \, ^{\circ}C$ 

(2)  $T_i = 25 \, ^{\circ}C$ 

Fig 9. Drain-source on-state resistance as a function of gate-source voltage; typical values



 $V_{DS} > I_D x R_{DSon}$ 

(1) 
$$T_j = 25 \,{}^{\circ}\text{C}$$

(2) 
$$T_j = 150 \, ^{\circ}\text{C}$$

Fig 10. Transfer characteristics: drain current as a function of gate-source voltage; typical values

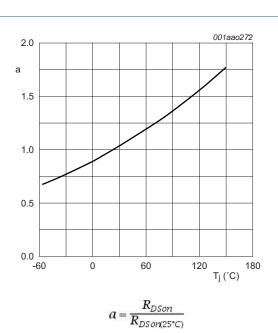
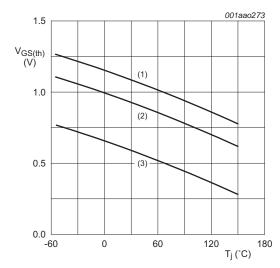


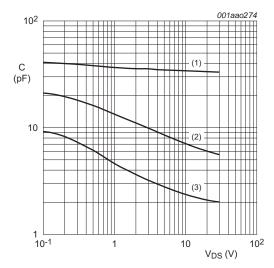
Fig 11. Normalized drain-source on-state resistance as a function of junction temperature; typical values



 $I_D = 0.25 \text{ mA}; V_{DS} = V_{GS}$ 

- (1) maximum values
- (2) typical values
- (3) minimum values

Fig 12. Gate-source threshold voltage as a function of junction temperature



 $f = 1 MHz; V_{GS} = 0 V$ 

(1)C<sub>iss</sub>

(2)Coss

(3)C<sub>rss</sub>

Fig 13. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

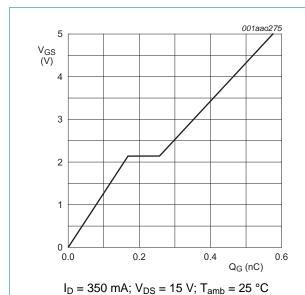


Fig 14. Gate-source voltage as a function of gate charge; typical values

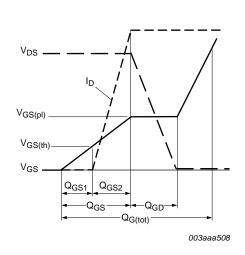
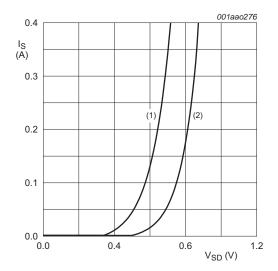


Fig 15. Gate charge waveform definitions



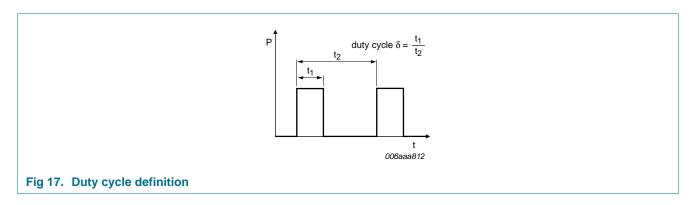
 $V_{GS} = 0 V$ 

(1)  $T_j = 150 \, ^{\circ}C$ 

(2)  $T_i = 25 \, ^{\circ}C$ 

Fig 16. Source current as a function of source-drain voltage; typical values

## 8. Test information



## 8.1 Quality information

This product has been qualified in accordance with the Automotive Electronics Council (AEC) standard *Q101 - Stress test qualification for discrete semiconductors*, and is suitable for use in automotive applications.

## 9. Package outline

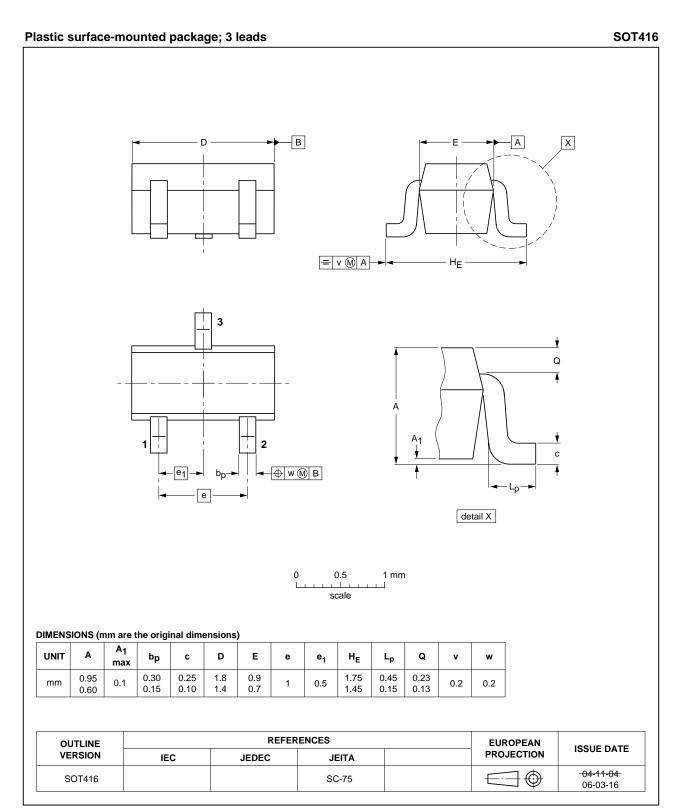
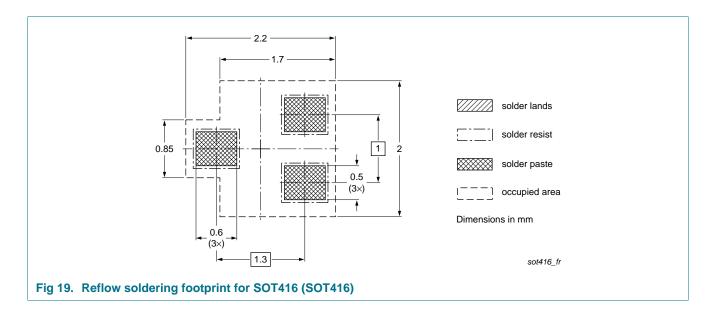


Fig 18. Package outline SOT416 (SOT416)

# 10. Soldering



NXP Semiconductors NX3008NBKT

30 V, 350 mA N-channel Trench MOSFET

# 11. Revision history

## Table 8. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
NX3008NBKT v.1	20110801	Product data sheet	-	-

## 12. Legal information

#### 12.1 Data sheet status

Document status [1] [2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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# NX3008NBKT

## 30 V, 350 mA N-channel Trench MOSFET

## 14. Contents

1	Product profile
1.1	General description
1.2	Features and benefits1
1.3	Applications1
1.4	Quick reference data1
2	Pinning information2
3	Ordering information2
4	Marking2
5	Limiting values3
6	Thermal characteristics5
7	Characteristics6
8	Test information10
8.1	Quality information
9	Package outline
10	Soldering
11	Revision history13
12	Legal information14
12.1	Data sheet status
12.2	Definitions14
12.3	Disclaimers
12.4	Trademarks15
13	Contact information15

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